ECE454/544: Fault-Tolerant Computing & Reliability Engineering

Lecture #14–

Dynamic Fault Trees

Instructor: Dr. Liudong Xing

Fall 2022

Administrative Issues

- Homework#6 assigned
  - Due by **Nov. 7, Monday**
- Project final report
  - Due by **Nov. 30, Wednesday**
  - Please check out the Report Guidelines for requirements

Review of Lecture #13

- Component sensitivity analysis measures the sensitivity of the system unreliability to the component failure parameters
  - Improvement Oriented: helps identify which components contribute most to the system reliability and thus they will be good candidates for efforts leading to improving system reliability, e.g.: Birnbaum's measure, improvement potential
  - Maintenance Oriented: helps identify the component that has the largest probability of being the cause of system failure → set up a repairperson's checklist, e.g.: criticality importance factor, diagnostic importance factor, Fussel-Vesley measure

Topics

- Dynamic fault trees

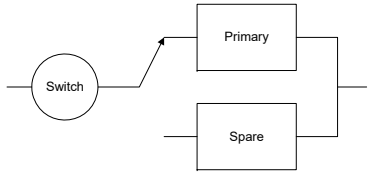
Reference:

J. B. Dugan and S. A. Doyle. "New Results in Fault-Tree Analysis" *Tutorial notes presented at Annual Reliability and Maintainability Symposium*, January 1997

J. B. Dugan, S. J. Bavuso, and M. A. Boyd, "Dynamic fault-tree models for fault-tolerant computer systems," IEEE Transactions on Reliability, vol.41, no.3, pp.363,377, Sep 1992

Dynamic Fault Trees

- Traditional (static) fault trees cannot model **sequence dependent** failures, in which the *order* that events occur is important.
- Sequence dependencies do exist in practical systems



  - Failure criteria depends on the *order* in which the failure occur.
- Special purpose gates were defined for modeling several kinds of dependencies (by Dugan et al.)

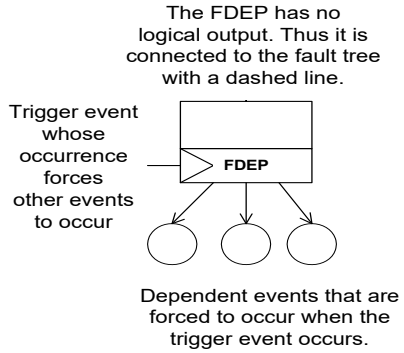
Dynamic Gates

- Functional dependency gate
- Cold spare gate
- Warm spare gate
- Hot spare gate
- Priority-AND gate

- Examples
  - Hypothetical Example Computer System (HECS)
  - Fault-Tolerant Parallel processor (FTPP)

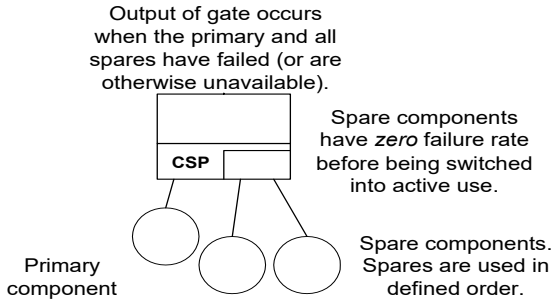
Functional Dependence Gate

- **Functional dependency**: the occurrence of some event (trigger event) causes other dependent components to become inaccessible or unusable
- **FDEP gate**:
  - separate occurrence of any of dependent basic events has no effect on the trigger event!

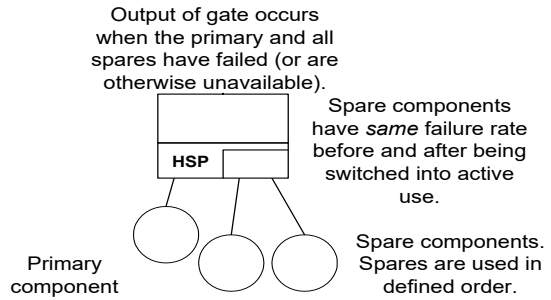


Cold Spare Gate (CSP)

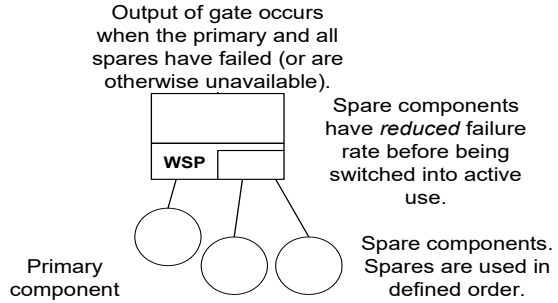
- **Cold spares**: spare components that are un-powered and thus do not fail before being used
- **CSP gate:**
  - One primary input and 1 or more alternate inputs
    - Every input is a basic event
    - The primary input is initially powered on
    - The alternate inputs specify components used as cold spares
  - One output becoming true after all input events occur



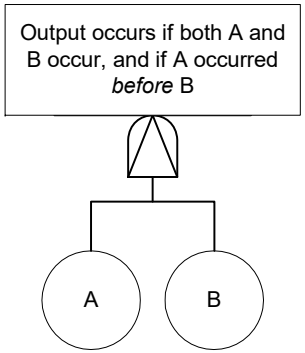
Hot Spare Gate (HSP)



Warm Spare Gate (WSP)



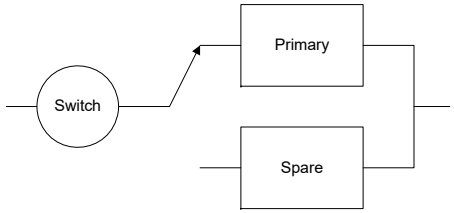
Priority-AND Gate (PAND)



- Logically equivalent to an AND gate, with an added condition that events must occur in a specific order
- To represent more than two events that must occur in a specific order to activate the output, the PAND gate can be cascaded.

Hands-On Problem

- Find the DFT model for the two-component standby sparing system. Assume the **cold sparing method** is used.

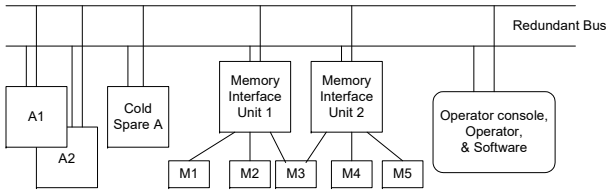


Dynamic Gates

- ✓ Functional dependency gate
- ✓ Cold spare gate
- ✓ Warm spare gate
- ✓ Hot spare gate
- ✓ Priority-AND gate

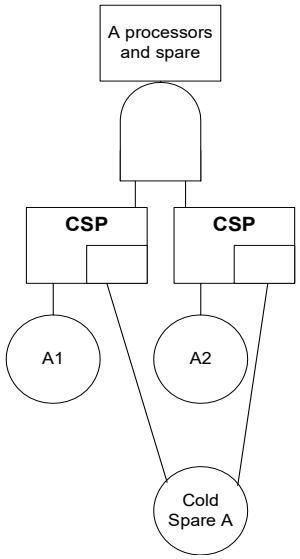
- Examples
  - **Hypothetical Example Computer System (HECS)**
  - Fault-Tolerant Parallel Processor (FTPP)

HECS: Hypothetical Example Computer System



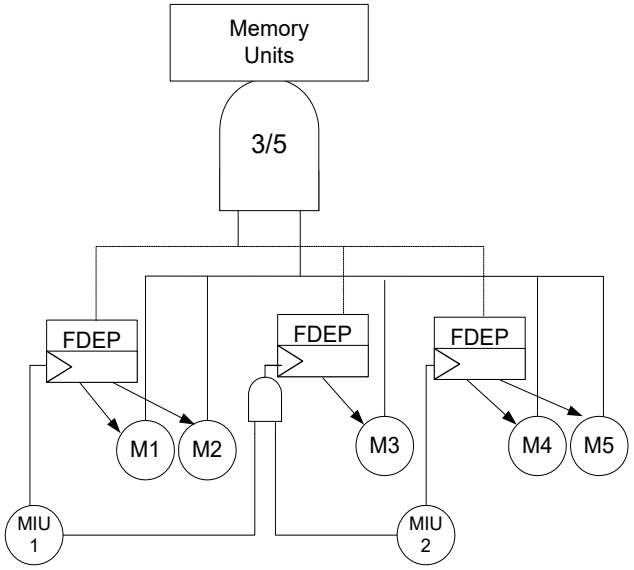
- Processors A1 and A2 share the cold spare A
- 3 out of the 5 memory units are needed; if MIU fails, memory is not accessible
- At least one bus is required
- HECS requires at least 1 of the three processors, at least 3 of the memory units, at least one of the redundant buses, and the operator, console and software to be operating correctly

Modeling the Processor Subsystem

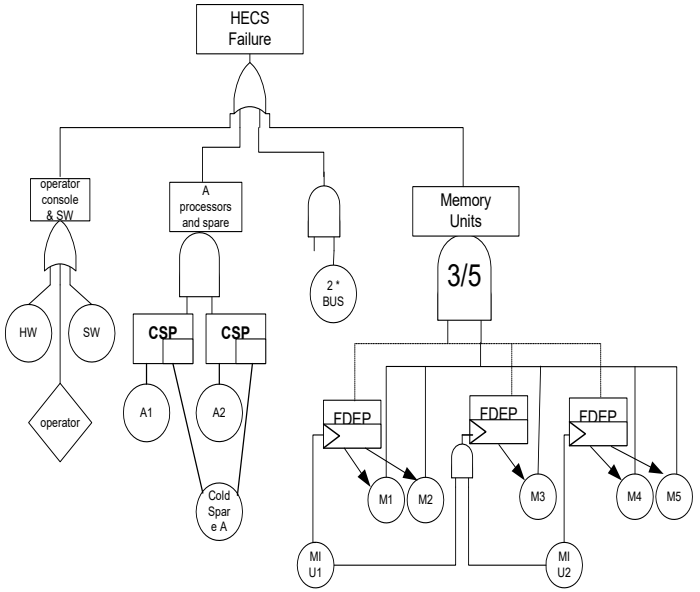


Note: the cold spare is shared between the two processors. First processor to fail is replaced with the spare; the spare is then unavailable if the other fails

Modeling the Memory Subsystem



Dynamic Fault Tree Model for HECS

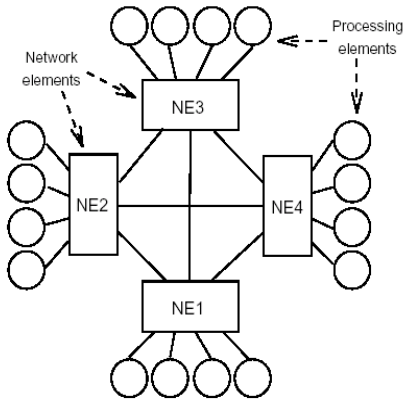


Dynamic Gates

- ✓ Functional dependency gate
- ✓ Cold spare gate
- ✓ Warm spare gate
- ✓ Hot spare gate
- ✓ Priority-AND gate

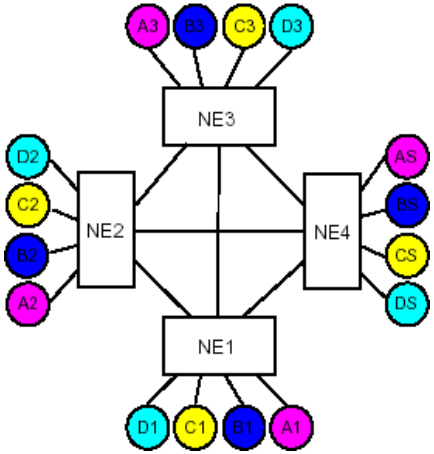
- Examples
  - √ Hypothetical Example Computer System (HECS)
  - – **Fault-Tolerant Parallel Processor (FTPP)**

Fault Tolerant Parallel Processor (FTPP, Lecture #1 Revisit)



- 16 processing elements (PE), with 4 connected to each of 4 network elements (NE)
- 16 PE form 4 triads, each with a spare
- NEs are fully connected
- Consider three configurations of the FTTP

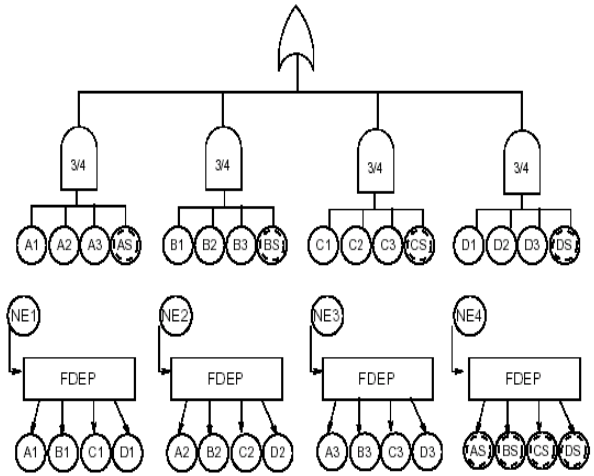
FTPP Configuration #1— 1 Spare per Triad



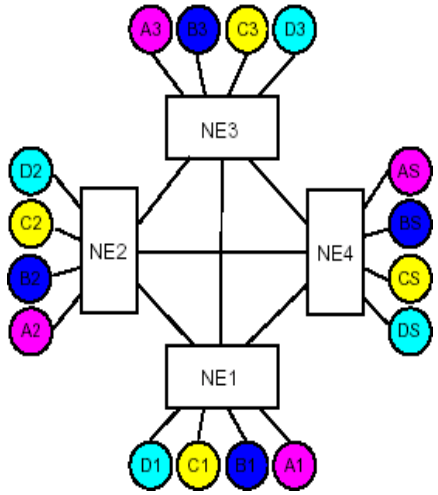
- Divides active elements of a triad among NE1, NE2, NE3; PEs in the same relative position on the first three NEs form a triad
- The PE in the same relative position on NE4 serves as a **hot spare** for the triad
  - One spare for each triad
  - All spares attached to the same network element NE4

DFT for FTPP Configuration #1

- All 4 triads must be operational to make the system operational
- And a triad fails when only one PE remains

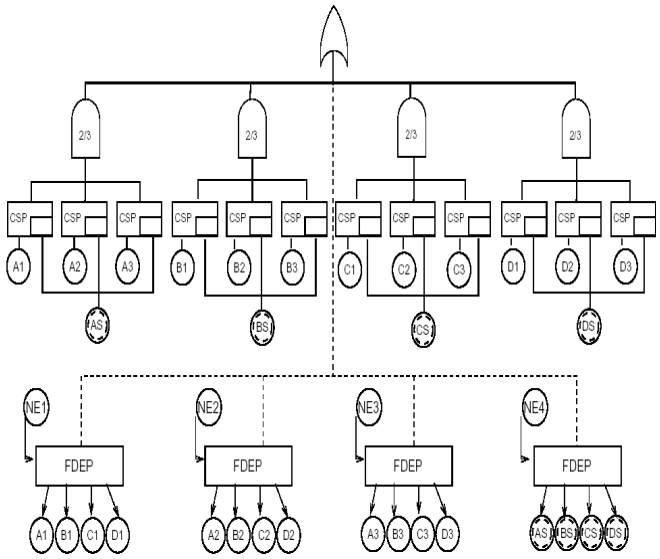


FTPP Configuration #2— #1 but Cold Spares



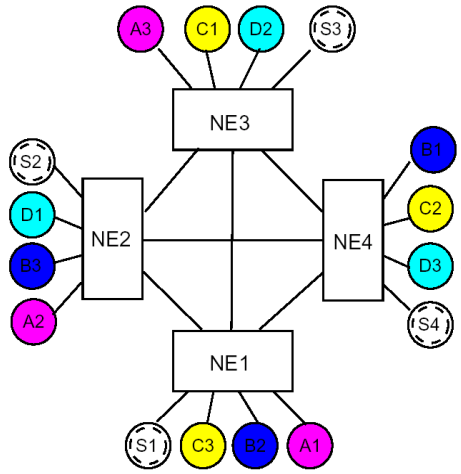
- One **COLD spare** for each triad
- All spares attached to the same network element NE4
- Used to investigate the effect on reliability of keeping spares unpowered until needed

DFT for Configuration #2



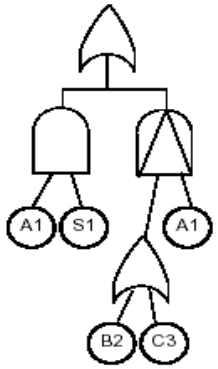
- The cold spare for each triad is connected to all three cold spare gates since it can substitute any of the elements

FTPP Configuration #3 – One Spare Per NE



- **Hot spares** distributed across the NEs
- The spare element on each NE can substitute for any failed PE connected to the same NE

Failure Conditions for FTPP #3



- The **first member of the A triad (A1) fails** if
  - both A1 and its spare (S1) fail
  - OR if either of the other processors on the same NE fail before A1 does, thus using the spare first. In this case there will be no spare available when A1 fails.
- Failure/success criteria of FTPP #3
  - All 4 triads must be operational to make the system operational
  - And a triad fails when only one PE remains

DFT for FTPP Configuration #3

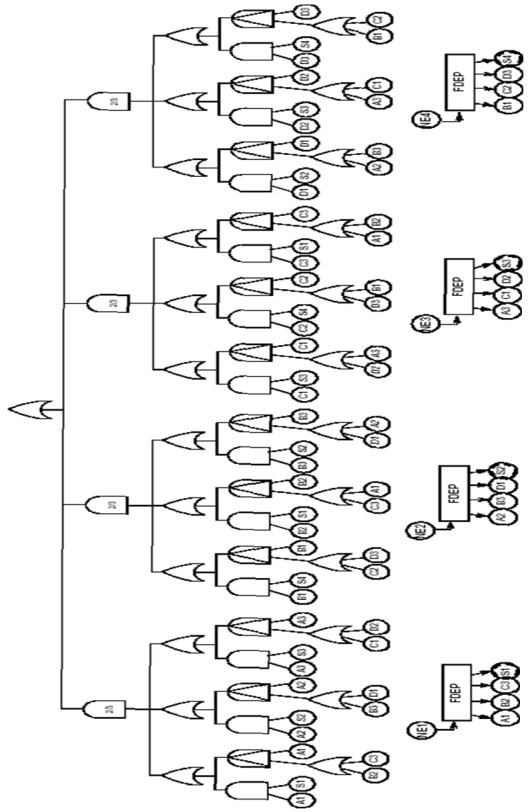


Figure 30 (Dugan97)

Summary of Lecture #14

- Special dynamic gates capture sequential dependencies arising in modeling fault tolerant systems
  - FDEP for modeling situations where one component's correct operation is dependent upon the correct operation of some other component
  - CSP for modeling cold spares which are unpowered before being used
  - WSP for modeling warm spares which fail at a reduced rate before being used
  - HSP for modeling hot spares which fail at active failure rate before being switched into active use
  - PAND for modeling ordered ANDing events
  - Two examples: HECS and FTPP
  - **Quantitative analysis of dynamic fault trees using Markov models will be the next topic!**

Next Topic

- Markov-based reliability analysis of DFT

Things to do

- Homework
- Project Report
  - Due **Wednesday, Nov. 30**
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